

<b>Notice of References Cited</b>	Application/Control No. 10/660,306		Applicant(s)/Patent Under Reexamination LIU, HEBEN	
	Examiner Christopher K. Agrawal		Art Unit 3726	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,516,867	02-2003	Ootori et al.	164/137
	B	US-			
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